



Committee on Education (Standing Committee of the NPC)

Chair: Bruce Harding, CEIR, Purdue University

Staff: Lisa Rajchel

Voting Members: (33)

Ms. Joyce Abrams, ASHRAE (2012)
Mr. Thomas Applegate, ACTE (2012)
Mr. Vince Baclawski, NEMA (2012)
Ms. Monica Barone, Qualcomm (2012)
Mr. Donald Deutsch, Oracle (2012)
Dr. Stephen J. Elliott, Purdue University (2012)
Ms. Joy Fitzpatrick, The Boeing Company (2012)
Dr. Richard Forselius, United Technologies Corporation (2012)
Ms. Dorothy Harris, ICC (2012)
Mr. Robert D. Hunter, P.E., Robert Hunter Assoc. (2012)
Mr. Frankie S. Jones, AT&T Business Learning Services (2012)
Mr. Stuart Karasik, Utilities Group (2012)
Ms. Liz Kerrigan, Infectious Diseases, ATCC (2012)
Mr. Stephen Kwan, San Jose University (2013)
Mr. Edward F. Mikowski, Jr., ECA (2012)
Ms. Ashley Moore, U.S. Dept. of Homeland Security (2012)
Mr. Steve Mutkoski, Microsoft (2012)

Dr. Christine Neiro, Professional Testing Inc. (2013)
Mr. Robert Noth (2012)
Mr. Jim Olshefsky, ASTM International (2013)
Ms. Deborah Prince, UL (2012)
Dr. Katherine D. Seelman, Univ. of Pittsburgh (2012)
Dr. Timothy Smith, University of Minnesota (2012)
Ms. Nancy Stark, Clinical Device Group (2012)
Ms. Jennifer Stradtman, U.S. DoC/ITA (2013)
Mr. Manfred Straehle, Green Building Certificate Inst. (2013)
Ms. Susan Tatiner, IEEE (2012)
Mr. Lee Webster, Society for HR Management (2012)
Mr. Jefferson Welch, Carnegie Mellon University (2012)
Mr. Philip Wennblom, Intel (2012)
Ms. Trudie Williams, U.S. DoD (2012)
Mr. George Willingmyre, GTW Associates (2012)
Mr. Donald Yarbrough, Educational Evaluation (2012)

Non-voting Members: (24)

Mr. John Bagby, Penn State University
Mr. Dan Bart, Valley View Corporation
Mr. Brad Biddle, Intel
Mr. Jorge Contreras, Contreras Legal Strategy LLC
Ms. Betsy Fanning, AIIM
Ms. Erin Grossi, Underwriters Laboratories
Mr. Stan Hazan, NSF International
Mr. David Hernandez, American Welding Society
Ms. Susan Hoyler, Qualcomm
Mr. Daryl Hunt, Eastman Kodak
Mr. Tim Koczanski, Department of Defense
Mr. John Kulick, Siemens Corporate Research

Mr. Bruce Mahone, SAE International
Ms. Jennifer McClain, IEEE
Mr. Alec McMillan, Rockwell Automation
Mr. Steve Mills, IEEE
Mr. Donald Purcell, The Center for Global Standards Analysis
Mr. Eric Puskar, NIST
Ms. Alison C. Ruger, IHS Global Inc.
Dr. John R. Sanders, JRS Consulting
Dr. Timothy Schoechle, ICSR, Univ. of Colorado
Ms. Anne Sharkey, Standards Council of Canada
Mr. John Toth, Intellectual Property Shield, Inc.
Mr. Glenn Tubrett, Canadian Standards Association